

<b>Search Notes</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10534536	FUKUSHIMA ET AL.
Examiner	Art Unit	
HENOK G HEYI	2627	

### SEARCHED

Class	Subclass	Date	Examiner

### SEARCH NOTES

Search Notes	Date	Examiner
Searched EAST and consulted with Primary Tan Dinh. Some of the subclasses searched are 369/275.1-4 and 428/64.1-4 (text search only - please see search history printout).	01/14/2009	HH

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

/HENOK G HEYI/  
Examiner.Alt Unit 2627